

Europe PV Automation Committee Meeting Summary and Minutes

SEMICON Europa
October 8, 2012
Dresden, Germany

Next Committee Meeting

March 13, 2013 - Berlin, in conjunction with PV FMF. Check www.semi.org/standards for the latest update.

Table 1 Meeting Attendees

Co-Chairs: Eberhard Teichmann (Peer Group)

SEMI Staff: Yann Guillou (SEMI Europe) / James Amano (SEMI HQ)

<i>Company</i>	<i>Last</i>	<i>First</i>	<i>Company</i>	<i>Last</i>	<i>First</i>
TEL	Asakawa	Terry	Entegris	Lundgren	Jorgen
Vitronic	Born	Carsten	TEL	Murakami	Takashi
AIS Automation	Fincke	Friedemann	TEL	Murata	Naoko
IE&S	Gyory	Istvan	Hennecke Systems	Schroll	Philip
Hennecke Systems	Hermann	Klaus	Peter Wagner consulting	Wagner	Peter
AIS Automation	Müller	Bert	PEER Group	Teichmann	Eberhard
BayTech Group	Baylies	Winthrop			

Table 2 Leadership Changes

<i>Group</i>	<i>Previous Leader</i>	<i>New Leader</i>
PV Automation co-chair	Martin Zennig	-
EIS TF	Martin Zennig	Carsten Born
Wafer Traceability TF	Istvan Gyory	Andreas Behr

Table 3 Ballot Results (or move to Section 4, Ballot Review)

Passed ballots and line items will be submitted to the ISC Audit & Review Subcommittee for procedural review.

Failed ballots and line items were returned to the originating task forces for re-work and re-balloting.

<i>Document #</i>	<i>Document Title</i>	<i>Committee Action</i>
5388	Revision to SEMI PV34-0712 with Title Change To: Practice for Assigning Identification Numbers to PV Si Brick, Wafer and Solar Cell Manufacturers	Passed as balloted
5418	Revision of SEMI PV29-0212, Specification for Front Surface Marking of PV Silicon Wafers with Two-Dimensional Matrix Symbols	Failed

Table 4 Authorized Ballots (or move to Section 7, New Business)

<i>#</i>	<i>When</i>	<i>SC/TF/WG</i>	<i>Details</i>
5418A	Cycle 1 2013	Wafer Traceability TF	Doc #5418 with a revised scope by adding a second method

Table 5 Authorized Activities (or move to Section 7, New Business)

<i>#</i>	<i>Type</i>	<i>SC/TF/WG</i>	<i>Details</i>
5418A	SNARF	Wafer Traceability TF	Revise the scope of doc #5418 by adding a second method to PV29 in the SNARF

Note: SNARFs and TFOFs are available for review on the SEMI Web site at:
<http://downloads.semi.org/web/wstdsbal.nsf/TFOFSNARF>

Table 6 New Action Items (or move to Section 8, Action Item Review)

<i>Item #</i>	<i>Assigned to</i>	<i>Details</i>
1008-01	Yann Guillou	Contact Wafer Traceability TF leader to see if he can take over Istvan Gyory
1008-02	Jorgen Lundgren	Contact Transport Carrier TF leaders and see if that is a reason not to sunset the TF

Table 7 Previous Meeting Actions Items (or move to Section 8, Action item Review)

<i>Item #</i>	<i>Assigned to</i>	<i>Details</i>
0613-01	James Amano	Minutes of previous TC meeting (PV FMF) to be corrected with regard to #5419 (no doc revision needed) – DONE, CLOSED
0613-02	Istvan Gyory	Send Marking Methodology short description activity to SEMI staff - NOT DONE but CLOSED

1 Welcome, Reminders, and Introductions

Eberhard Teichman called the meeting to order at 3pm. The meeting reminders on antitrust issues, intellectual property issues and holding meetings with international attendance were reviewed. Attendees introduced themselves.

2 Review of Previous Meeting Minutes

The committee reviewed the minutes of the previous meeting presented by Yann Guillou.

Motion: To accept the minutes as written
By / 2nd: Eberhard Teichmann / Friedemann Frincke
Discussion: None
Vote: 12/0 - PASSED

3 Liaison Reports

3.1 Japan PV Automation Committee

Terry Asakawa reported for the Japan PV Automation Committee. Of note:

- Doc. 4804A was adjudicated in Japan in September 2012 and passed ballot review. Standard will be published as PV035. Liaison report is enclosed.

Attachment: 1, JP_PVAuto_to_EU_PVC_Oct8_r0.1

4 SEMI Staff Report

James Amano gave the SEMI Staff Report. Of note:

He presented the calendar of upcoming events, the 2013 preliminary cycle dates. He touched base on the new templates, the new revision of the style manual, and new compilation of terms. He informed attendees Europe could have up to 4 representatives in the A&R Standard Committee.

Attachment: 2, SEMI Staff Report SEMICON Europa Oct 2012 v2

5 Ballot Review

5.1 Document # 5388, Revision to SEMI PV34-0712 with Title Change To: Practice for Assigning Identification Numbers to PV Si Brick, Wafer and Solar Cell Manufacturers

- 1 comment received.

Motion: Document to be approved as balloted and forwarded to ISC A&R subcommittee for procedural review

By / 2nd: Peter Wagner / Winthrop Baylies

Discussion: None

Vote: 12 / 0 - PASSED

- Document passed technical review and is being forwarded to the ISC A&R Subcommittee for procedural review. See attachment below for details of ballot adjudication.

Attachment: 3, A&R5388

5.2 Document # 5418, Revision of SEMI PV29-0212, Specification for Front Surface Marking of PV Silicon Wafers with Two-Dimensional Matrix Symbols

- 2 rejects were received. One reject was evaluated as related and technically persuasive, one was evaluated as related but not technically persuasive.

Motion: To fail the document

By / 2nd: Itsvan Gyory / Peter Wagner

Discussion: None

Vote: 8 / 0 - PASSED

- Document failed.

6 Subcommittee & Task Force Reports

6.1 PV Traceability TF

6.1.1 SNARF Doc. 5418A: Revise the scope of doc #5418 by adding a second method to PV29

Motion: To approve SNARF

By / 2nd: Itsvan Gyory / Peter Wagner

Discussion: None

Vote: 9 / 0 – PASSED

6.1.2 Authorized Activity

Motion: Document 5814A to be submitted for ballot in cycle 1 and be adjudicated during PV FMF PV Standard Meetings – March 2013

By / 2nd: Peter Wagner / Winthrop Baylies

Discussion: None

Vote: 9 / 0 – PASSED

6.1.3 Leadership change

Itsvan Gyory will stop his job as TF leader. He will continue as a contributor in the drafting on doc 5814A.

6.2 PV EIS TF

5.2.1 Carsten Born gave the status on doc. 5153, 5154, 5339, 5151, and 5223. Of note:

- Doc. 5339: Recommendation to postpone the activity.
- Doc. 5151: Recommendation to fail the SNARF. This item will be discussed at the next meeting.
- Doc. 5223: EU PV EIS will share ideas and initiate discussions with Japan TF.

Attachement: 4, Device_Integration_en.pdf

5.2.2 Leadership change

Martin Zennig stepped down from his TF leadership position.

Motion: To approve Carsten Born as new TF leader

By / 2nd: Eberhard Teichmann / Jorgen Lundgren

Discussion: No

Vote: 12/0 - PASSED

Carsten Born was appointed new PV EIS TF leader.

6.3 PV Transport Carrier TF

- Jorgen Lundgren contacted representatives from Q-Cells and Fraunhofer that were leading this TF with him. No answers.
- Jorgen Lundgren presented the investigations that were started some time ago and never completed.
- Jorgen Lundgren took the action to try to reach the TF leader.

7 New Business

7.1 Discussion: SNARF to modify PV02

- SNARF will be prepared if modification of SEMI E30 passed in cycle 6 2012.

7.2 Definition of new activity:

- None

8 Action Item Review

8.1 Open Action Items

Yann Guillou (SEMI) reviewed the open action items. These can be found in the Open Action Items table at the beginning of these minutes.

8.2 New Action Items

Yann Guillou (SEMI) reviewed the new action items. These can be found in the New Action Items table at the beginning of these minutes.

9 Next Meeting and Adjournment

Next PV Automations meeting will occur in conjunction with PV Fab Manager Forum in Berlin (10th-12th March, 2013). PV standard meetings are planned on the 12th and 13th 2013.

For more information about SEMI Standard meeting during PV Fab Manager Forum, please visit:
<http://www.pvgroup.org/Events/p040664>

Eberhard Teichman adjourned the meeting at 4.50pm.

Minutes respectfully submitted by:

Yann Guillou
Business Development and Standard Manager
SEMI Europe
Phone: +33 (0)4 38 78 39 71
Email: yguillou@semi.org

Minutes approved by:

Eberhard Teichman (Peer Group) Co-chair	<Date approved>
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#	<i>Title</i>
1	JP_PVAuto_to_EU_PVC_Oct8_r0.1
2	SEMI Staff Report SEMICON Europa Oct 2012 v2
3	A&R5388
4	Device_Integration_en.pdf

#1 Due to file size and delivery issues, attachments must be downloaded separately. A .zip file containing all attachments for these minutes is available at www.semi.org. For additional information or to obtain individual attachments, please contact [SEMI Staff Name] at the contact information above.